



## Descriptions

The NVT4557HKX device is built for interfacing a SIM card with a single low-voltage 1.0V to 1.8 V host side interface. The NVT4557HKX contains three 1.62 V to 3.6 V level translators to convert the data, RSTn and CLKn signals between a SIM card and a host microcontroller. The NVT4557HKX is compliant with all ETSI, IMT-2000 and ISO-7816 SIM/Smart card interface requirements.

## Order Information

Package		Part Number	Top-Side Marking
QFN1418(XQFN-10(1.4x1.8))	Tape and Reel	NVT4557HKX	#####

## Features

- Supports clock speed up to 10 MHz clock
- Compliant with all ETSI, IMT-2000 and ISO-7816 SIM/Smart card interface requirements
- Support SIM card supply voltages with range of 1.62 V to 3.6 V
- Host microcontroller operating voltage range: 1.08 V to 1.98 V
- Automatic level translation of I/O, RSTn and CLKn between SIM card and host side interface with capacitance isolation
- Incorporates shutdown feature for the SIM card signals according to ISO-7816-3
- Automatic enable and disable through VCCB (Enable pin on A4557 Q 10 pin package only)
- Integrated pull-up and pull-down resistors: no external resistors required
- Integrated EMI filters suppress higher harmonics of digital I/Os
- Integrated 8 kV ESD protection according to IEC 61000-4-2, level 4 on VCCB or any of the card side pins. External ESD diodes are not required.
- Level shifting buffers keep ESD stress away from the host (zero-clamping concept)
- Pb-free, Restriction of Hazardous Substances (RoHS) compliant and free of halogen and antimony (Dark Green compliant)
- Available in 10-pin QFN10 package with 0.4mm pitch

## Applications

- Mobile, Smart phones and Wireless modems
- SIM card terminals



## Functions and Pin Configuration

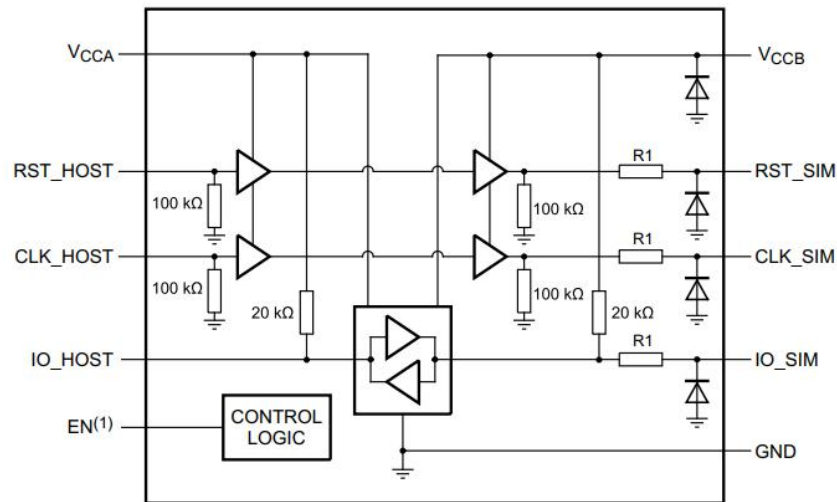


Fig.1 Functional Diagram

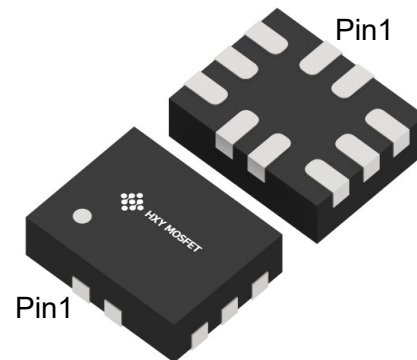
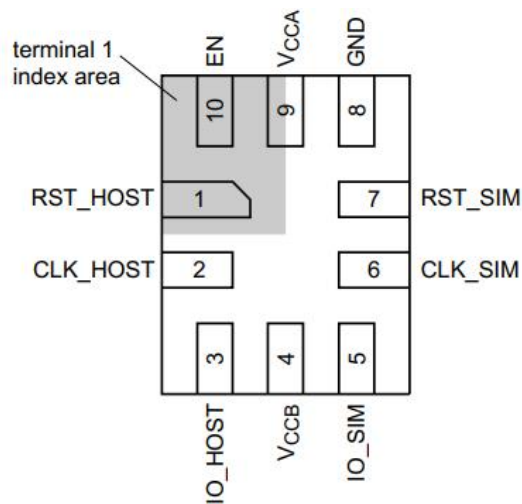


Fig.2 QFN1418(XQFN-10(1.4x1.8))



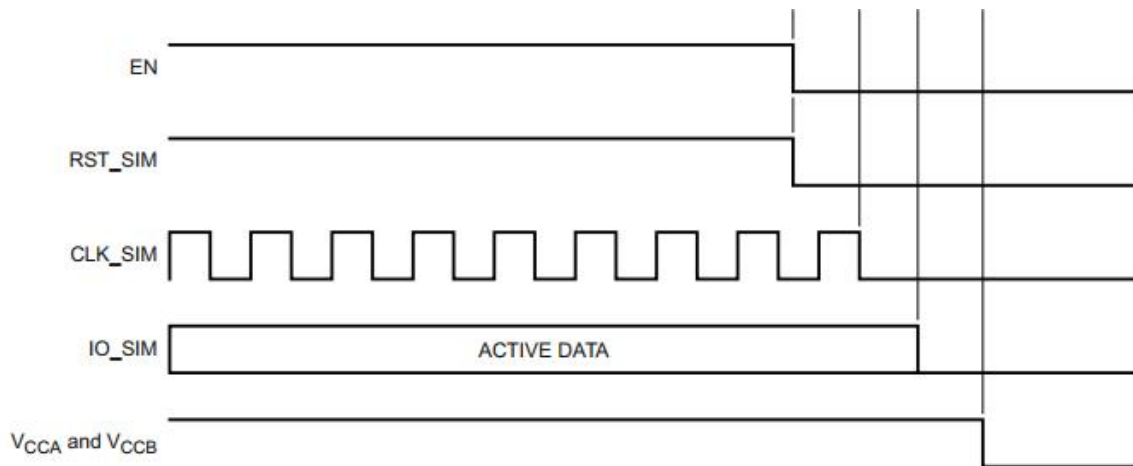
### Pin Descriptions

Name	Pin for CSP	Pin for QFN	Type	Description
RST_HOST	A1	1	I	Reset input from host controller
VCCA	A2	9	Supply	Supply voltage for the host controller side input/output pins (CLK_HOST, RST_HOST, IO_HOST). This pin should be bypassed with a 0.1 $\mu$ F ceramic capacitor close to the pin.
RST_SIM	A3	7	O	Reset output pin for the SIM card
CLK_HOST	B1	2	I	Clock input from host controller
GND	B2	8	GND	Ground for the SIM card and host controller. Proper grounding and bypassing are required to meet ESD specifications
CLK_SIM	B3	6	O	Clock output pin for the SIM card
IO_HOST	C1	3	I/O	Host controller bidirectional data input/output. The host output must be on an open-drain driver
VCCB	C2	4	Supply	SIM card supply voltage. When VCCB is below the VCCBdisable, the device is disabled. This pin should be bypassed with a 0.1 $\mu$ F ceramic capacitor close to the pin
IO_SIM	C3	5	I/O	SIM card bidirectional data input/output. The SIM card output must be on an open-drain driver
EN	---	10	I	Host controller driven enable pin. This pin should be HIGH (VCCA) for normal operation, and LOW to help avoid race conditions specifically during the shutdown sequence. (Only on 10 pin version - for 9 pin version EN is pulled to VCCA.)

**Table-1 Pin Descriptions**

### Shutdown Sequence of NVT4557HKX (10-pin version only)

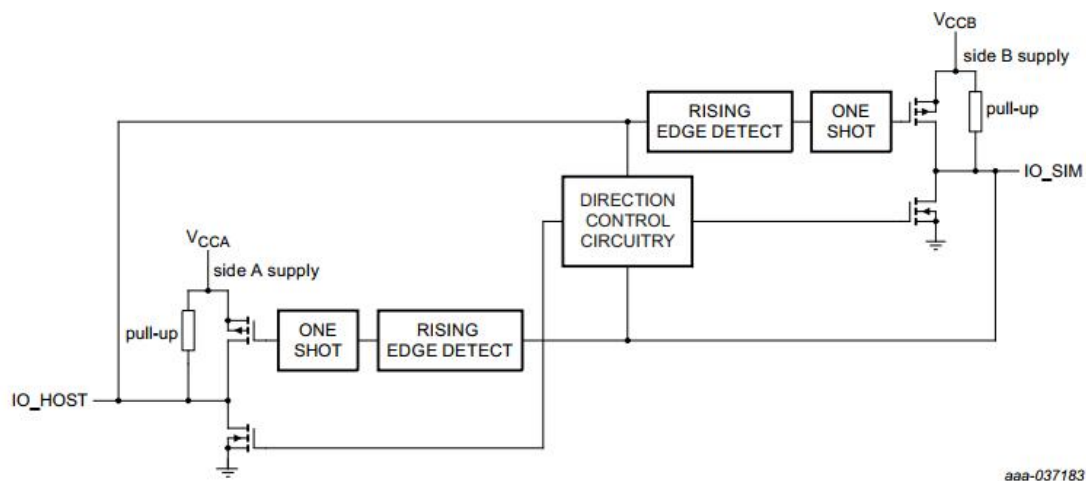
The ISO 7816-3 specification specifies the shutdown sequence for the SIM card signals to ensure that the card is properly disabled for power savings. Also during hot swap, the orderly shutdown of these signals helps to avoid any improper write and corruption of data. When the enable, EN, is asserted LOW, the shutdown sequence is initiated by powering down the RST\_SIM channel. Once the RST\_SIM channel is powered down, CLK\_SIM and IO\_SIM are powered down sequentially one-by-one. An internal pull-down resistor on the SIM pins is used to pull these channels LOW. The shutdown sequence is completed in a few microseconds. It is important that EN is pulled LOW before VCCA and VCCB supplies go LOW to ensure that the shutdown sequence is properly initiated.



**Fig.3 Shutdown sequence for RST\_SIM, CLK\_SIM, IO\_SIM and VCCA/VCCB**

## Level Translator Stage

The architecture of the device I/O channel is shown below. The device does not require an extra input signal to control the direction of data flow from host to SIM or from SIM to host. As a change of driving direction is just possible when both sides are in HIGH state, the control logic is recognizing the first falling edge granting it control about the other signal side. During a rising edge signal, the non-driving output is driven by a one shot circuit to accelerate the rising edge. In case of a communication error or some other unforeseen incident that would drive both connected sides to be drivers at the same time, the internal logic automatically prevents stuck-at situation, so both I/Os will return to HIGH level once released from being driven LOW. The channels RST and CLK just contain single direction drivers without the holding mechanism of the I/O channel, as these are just driven from the host to the card side.



**Fig.4 Automatic direction control level translator for HIGH-level direction change interfaces**



**Electrical Characteristics** (Ta=25°C, V<sub>VCCA</sub>=1.0V~1.8V, V<sub>VCCB</sub>=1.62V~3.6V, unless otherwise specified)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Power Supplies						
VCCA	Host Side Supply		1.0		1.98	V
VCCB	SIM Side Supply		1.6		3.6	V
VVCCA_U VLO	VCCA Under Voltage Lockout	Rising, 100mV hysteresis	0.6	0.7	0.8	V
VVCCB_U VLO	VCCB Under Voltage Lockout	Rising. 100mV hysteresis	1.3	1.4	1.5	V
ISD_VCCA	Shutdown Current EN=0V	VCCA=1.2V		0.5	1	uA
ISD_VCCB		VCCB=1.8V		0.5	1	uA
IQ_VCCA	Quiescent Current EN=VCCA	VCCA=1.2V, CLK_HOST=0V		0.5	1	uA
IQ_VCCB		VCCB=1.8V, CLK_HOST=0V		0.5	1	uA
I <sub>ACT_VCC</sub> A	Active Current EN=VCCA	VCCA=1.2V, CLK_HOST=1MHz CL= 30pF		5	10	uA
I <sub>ACT_VCC</sub> B		VCCB=1.8V, CLK_HOST=1MHz CL= 30pF		250	300	uA
Logic I/O pin (EN)						
V <sub>IH</sub>	High-Level Input Voltage	EN pin	0.7*VCCA			V
V <sub>IL</sub>	Low-Level Input Voltage	EN pin			0.3*VCC A	V
Level Translator (Host Side)						
V <sub>IH</sub>	High Level input voltage	IO_HOST, RST_HOST, CLK_HOST	0.7*VCCA			V
V <sub>IL</sub>	Low Level input Voltage	IO_HOST, RST_HOST, CLK_HOST			0.3*VCC A	V
V <sub>OH</sub>	High Level output voltage	IO_HOST, IOH_IO=20uA	0.8*VCCA			V
V <sub>OL</sub>	Low Level output voltage	IO_HOST, IOL_IO=20uA			0.2*VCC A	V
R <sub>PUA</sub>	Pull up resistance	IO_HOST connected to VCCA	6	8	10	kΩ
Level Translator (SIM Card Side)						
V <sub>IH</sub>	High Level input voltage	IO_SIM	0.7*VCCB			V
V <sub>IL</sub>	Low Level input Voltage	IO_SIM			0.3*VCC B	V
V <sub>OH</sub>	High Level output voltage	CLK_SIM, RST_SIM, IOH=20uA	0.8*VCCB			V
		IO_SIM, IOH=20uA	0.8*VCCB			V
V <sub>OL</sub>	Low Level output voltage	CLK_SIM, RST_SIM, IOL =- 1mA			0.125* VCCB	V
		IO_SIM, IOL =-1mA			0.125* VCCB	V



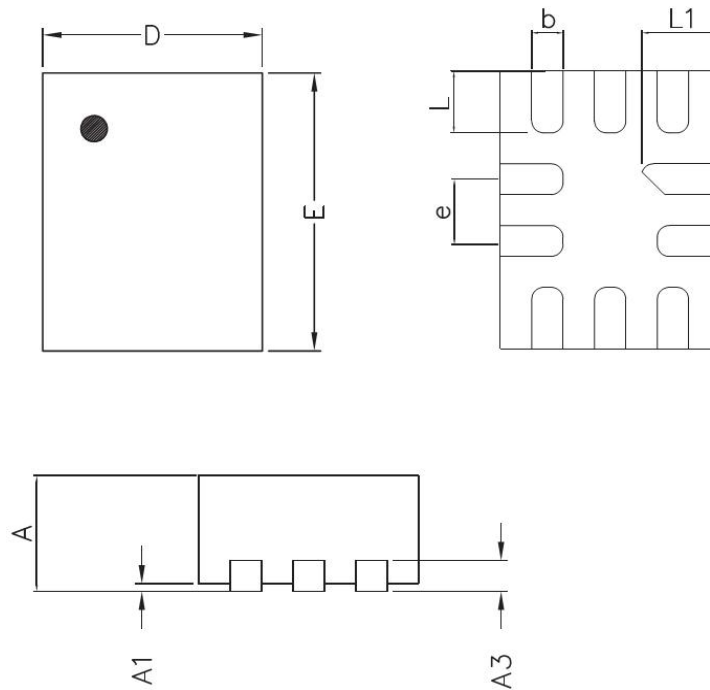
R <sub>PUB</sub>	Pull up resistance	IO_SIM connected to VCCB	12	20	30	kΩ
R <sub>s</sub>	Series resistance	IO_SIM, RST_SIM, CLK_SIM	40	55	100	Ω
R <sub>pD</sub>	Pull down resistance	IO_SIM, RST_SIM, CLK_SIM when EN is driven low		4		kΩ
Dynamic Characteristics (CL=30pE in Host side, CL=30Pf in SIM side, VCCA=1.8V, VCCB=3.0V)						
t <sub>PD</sub>	Propagation delay	From Host side to SIM side		10	20	ns
t <sub>PD</sub>	Propagation delay	From SIM side to HOST side		10	20	ns
t <sub>r_B</sub>	RST_SIM Rising time	From 10% to 90% of VCCB=3.0V		8	15	ns
	CLK_SIM Rising time	From 10% to 90% of VCCB=3.0V		8	15	ns
	IO_SIM Rising time	From 10% to 90% of VCCB=3.0V		8	15	ns
t <sub>r_B</sub>	RST_SIM falling time	From 90 %to 10% of VCCB=3.0V		8	15	ns
	CLK_SIM falling time	From 90 %to 10% of VCCB=3.0V		8	15	ns
	IO_SIM falling time	From 90 %to 10% of VCCB=3.0V		8	15	ns
t <sub>r_A</sub>	IO_HOST rising time	From 10% to 90% of VCCA=1.8V		8	15	ns
t <sub>r_A</sub>	IO_HOST falling time	From 90 %to 10% of VCCA=1.8V		8	15	ns
t <sub>EN</sub>	Enable timing	From EN High to RST_High			100	ns
t <sub>RST_DIS</sub>	RST_SIM Disable time	From EN Low to RST_SIM low		200		ns
t <sub>CLK_DIS</sub>	CLK_SIM Disable time	From EN low to CLK_SIM low		15		us
t <sub>IO_DIS</sub>	IO_SIM Disable time	From EN low to IO_SIM low				us
f <sub>CLK</sub>	CLK_HOST frequency				10	MHZ

Table-2 Electrical Characteristics



## Package Outline Dimensions

### QFN1418(XQFN-10(1.4x1.8))



Symbol	Dimension in Millimeters	
	Min.	Max.
A	0.450	0.550
A1	0.000	0.050
A3	0.152 Ref.	
D	1.350	1.450
E	1.750	1.850
b	0.150	0.250
e	0.400 Typ.	
L	0.350	0.450
L1	0.450	0.550



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